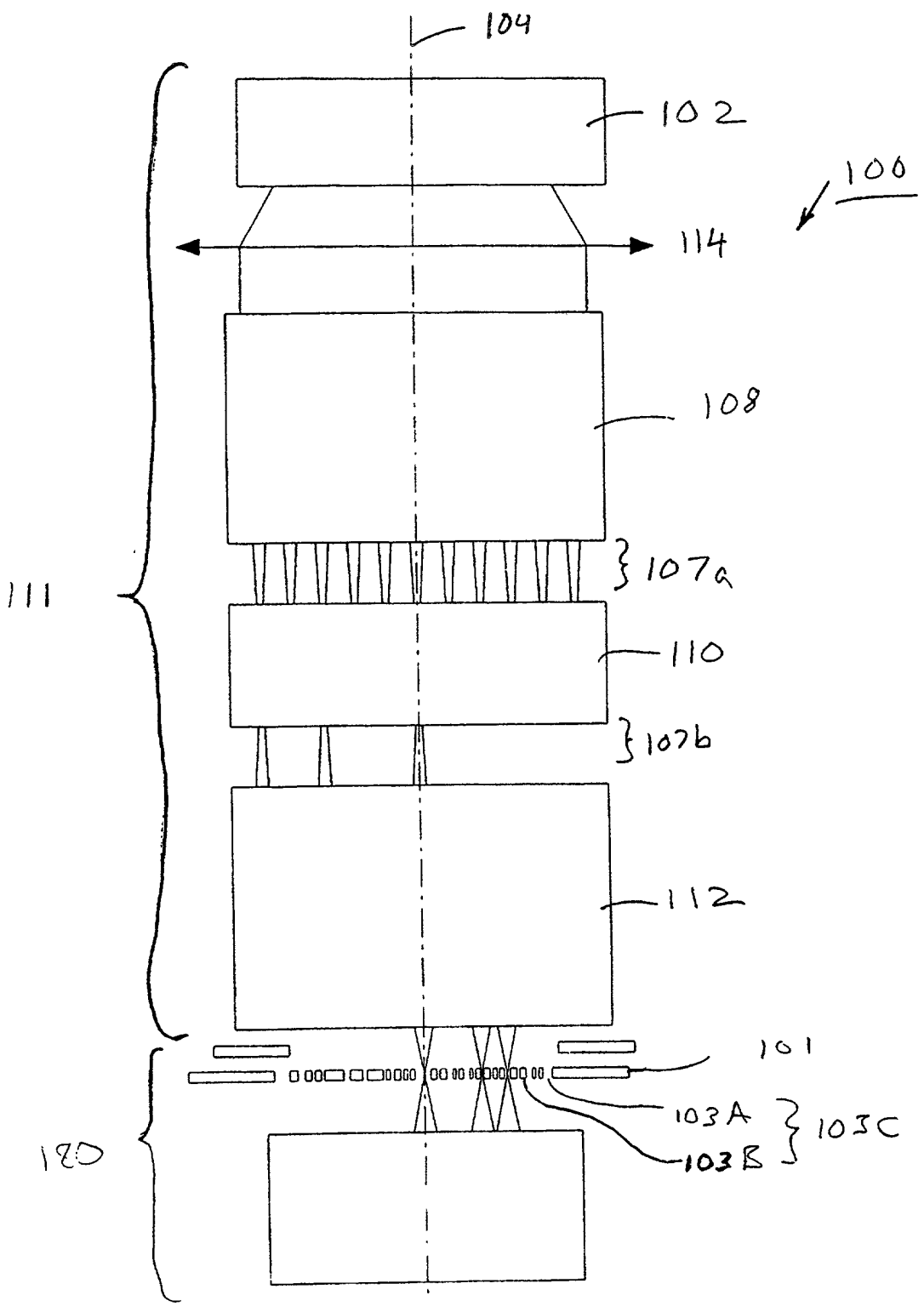


10066379 "104801"



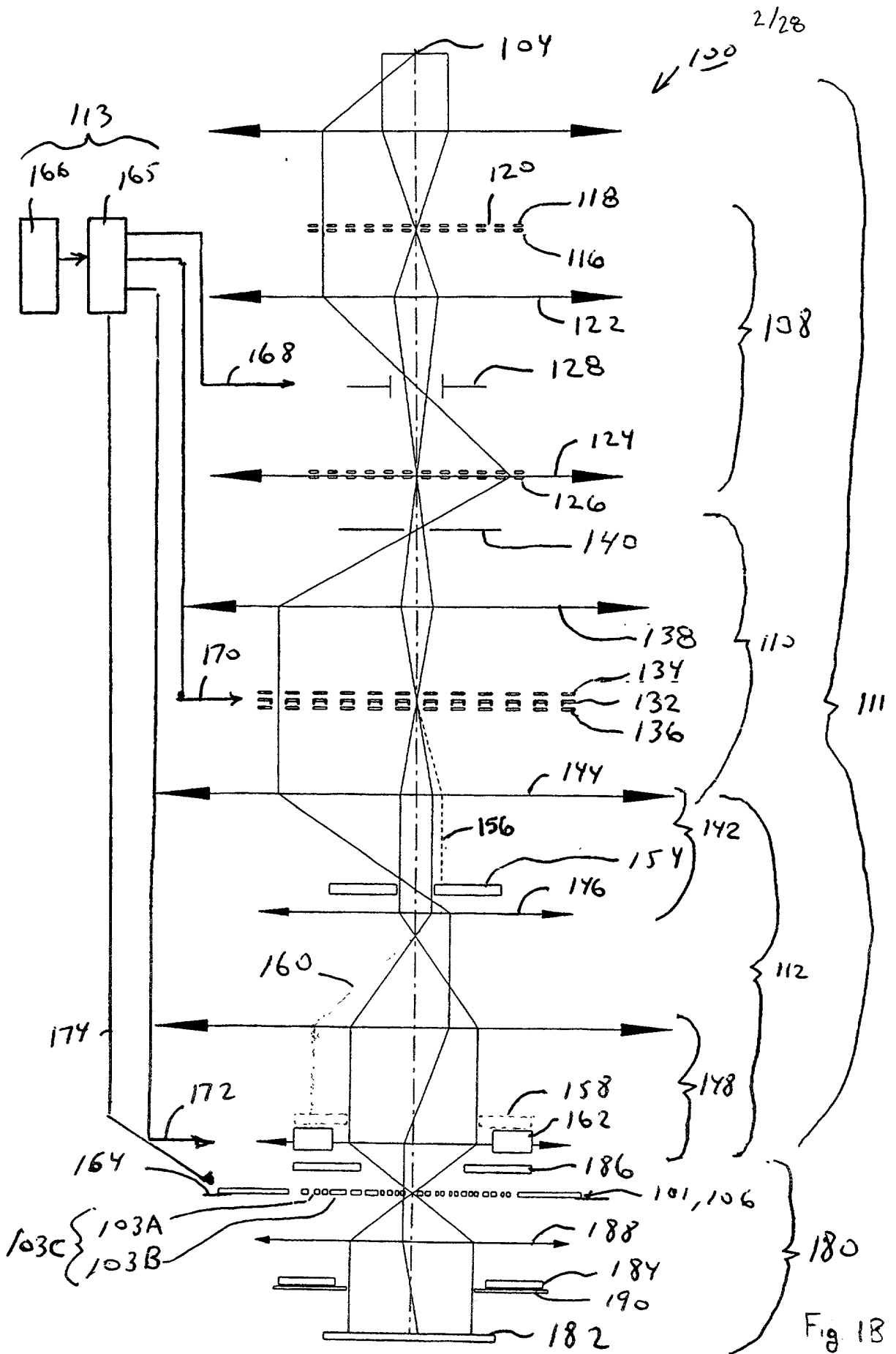


FIG. 2

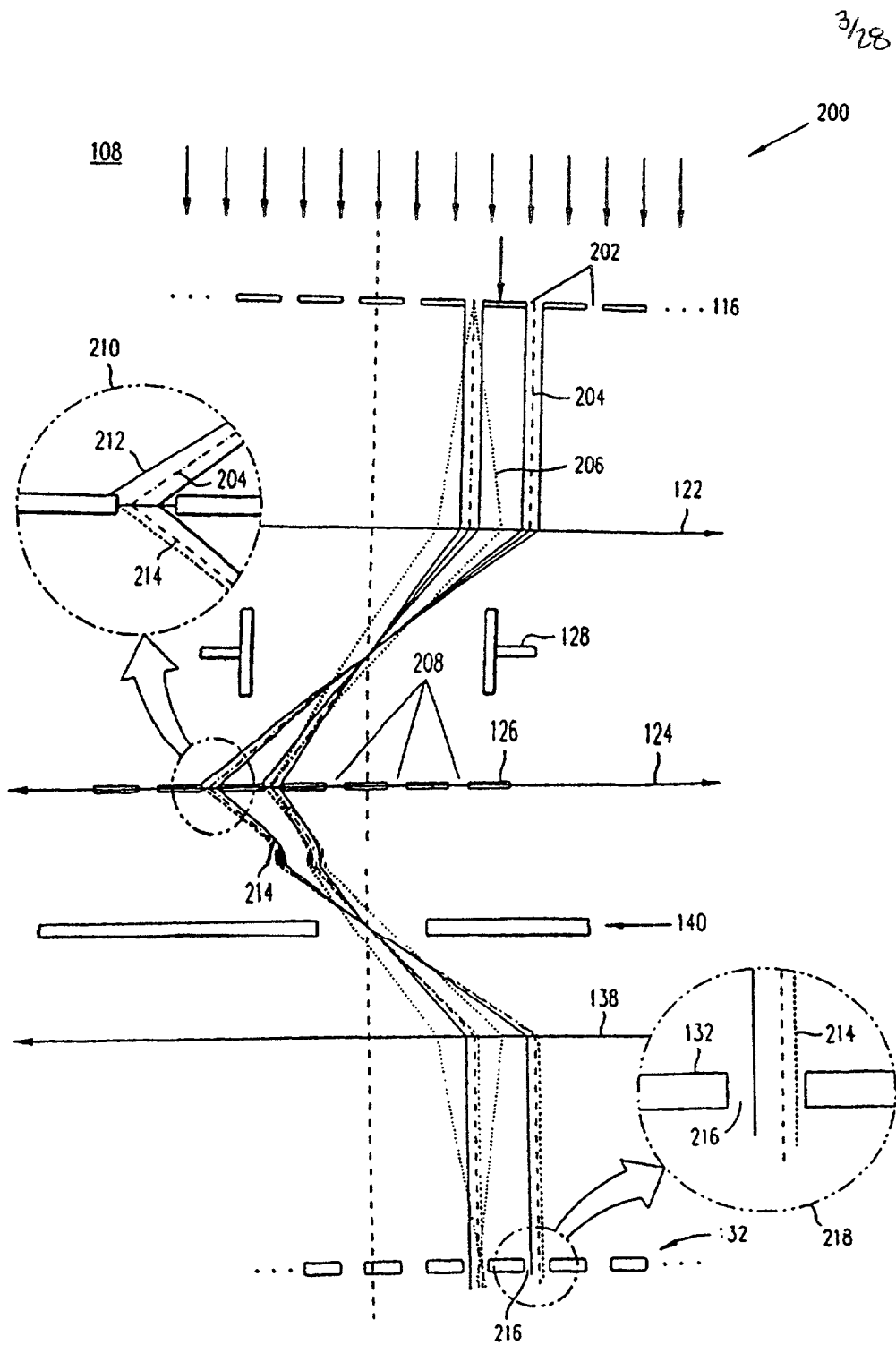


FIG. 2

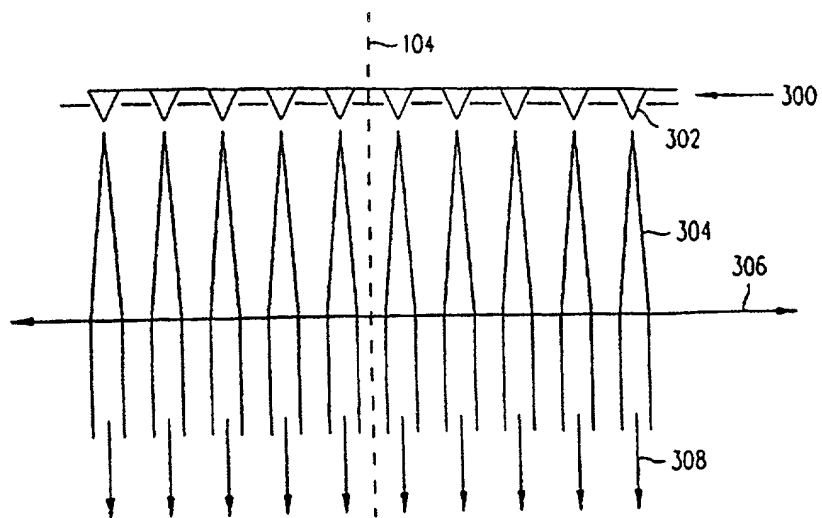


FIG. 3A

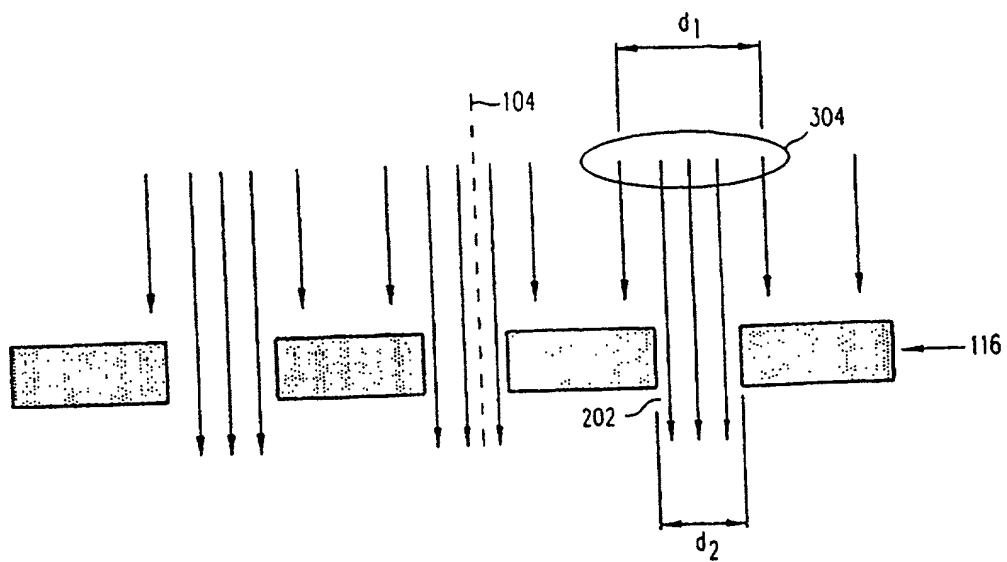
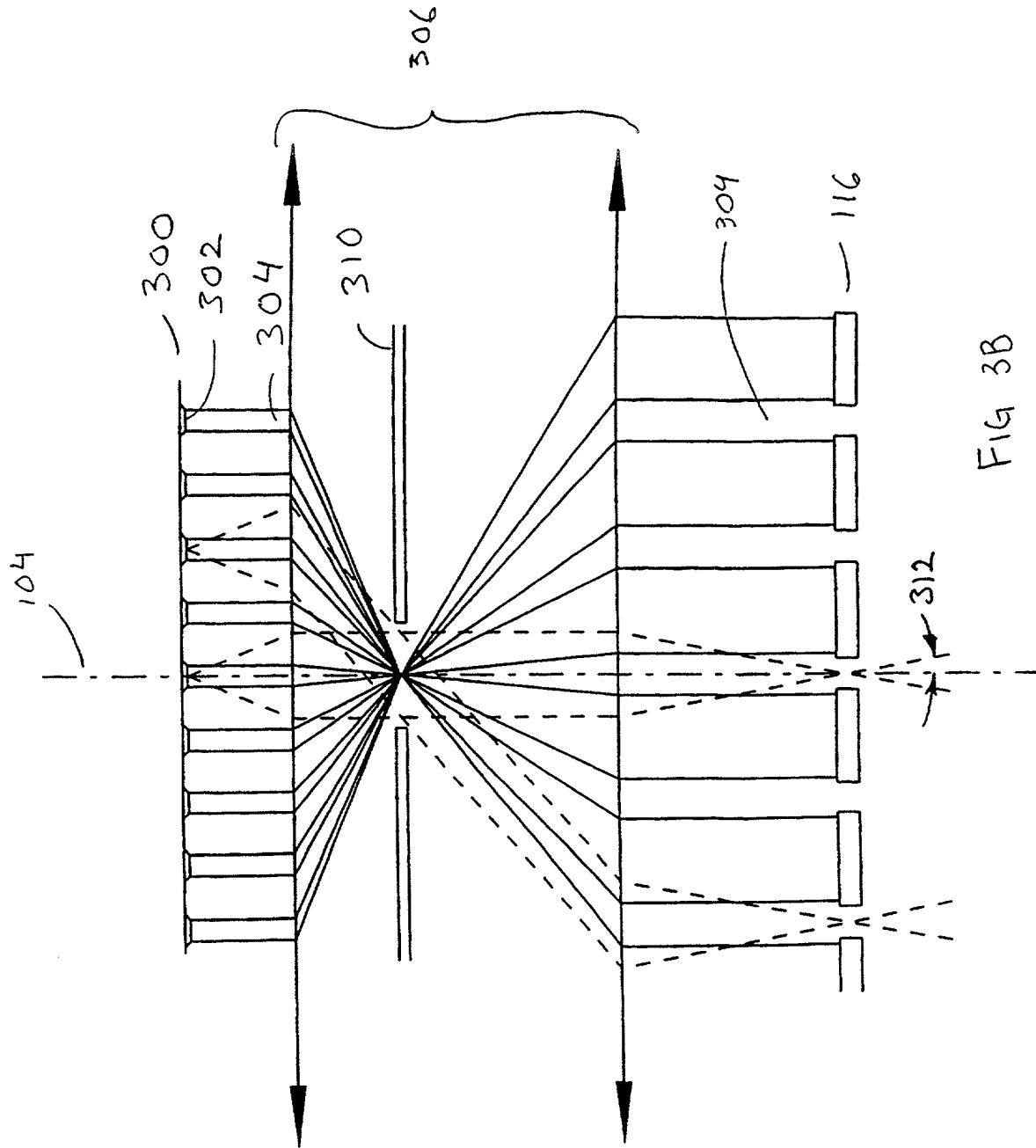
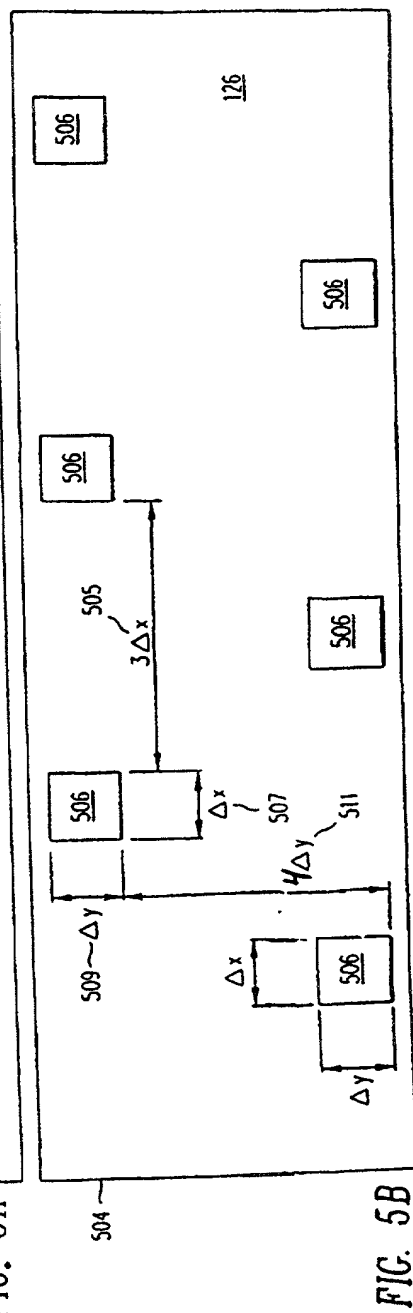
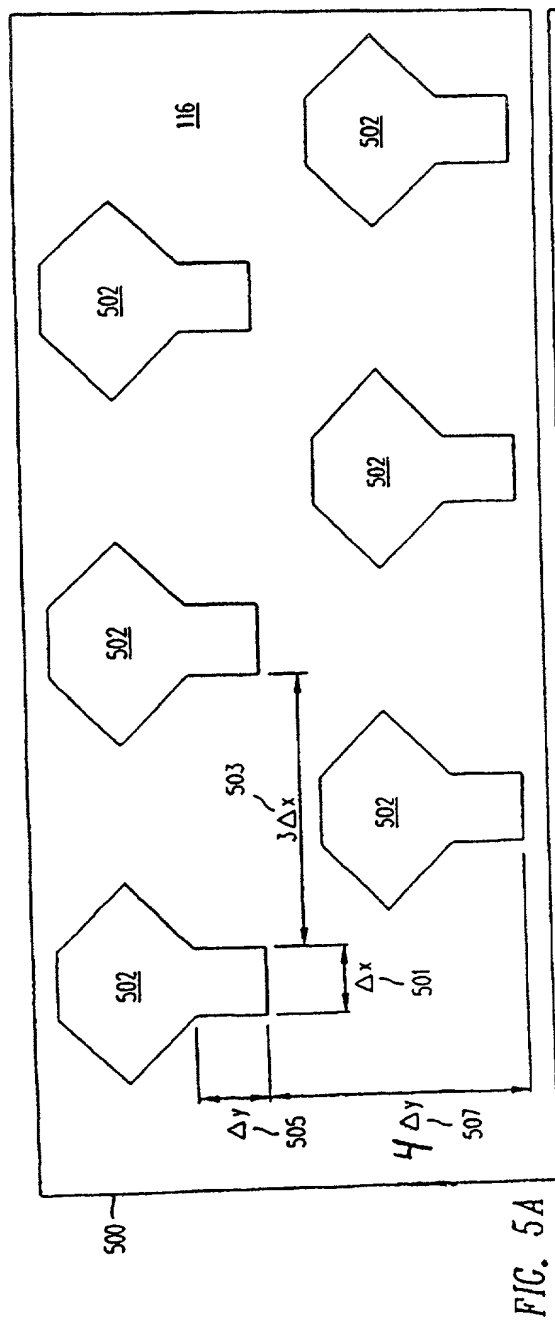


FIG. 4





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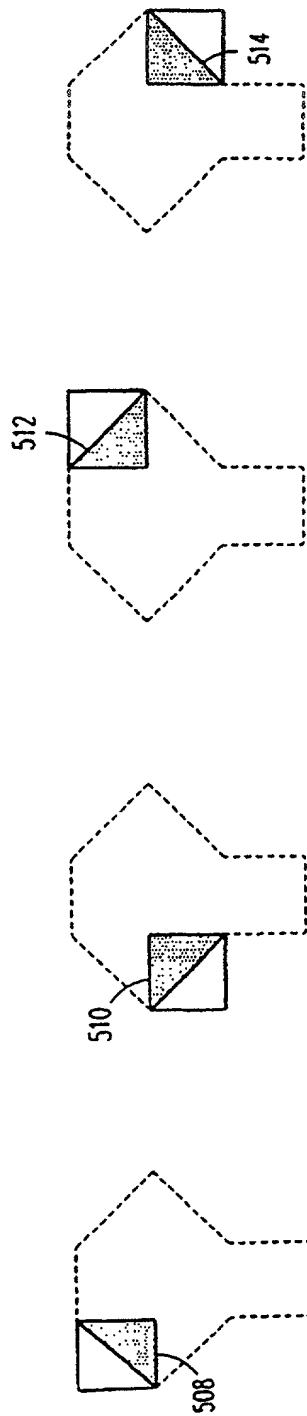


FIG. 5C

FIG. 5D

FIG. 5E

FIG. 5F

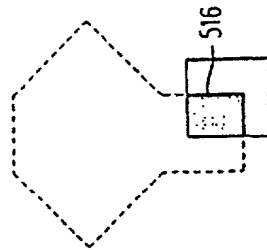


FIG. 5G

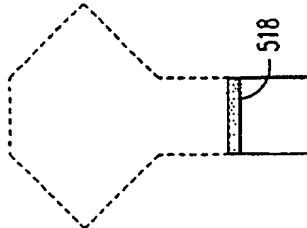


FIG. 5H

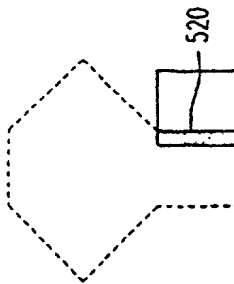


FIG. 5I

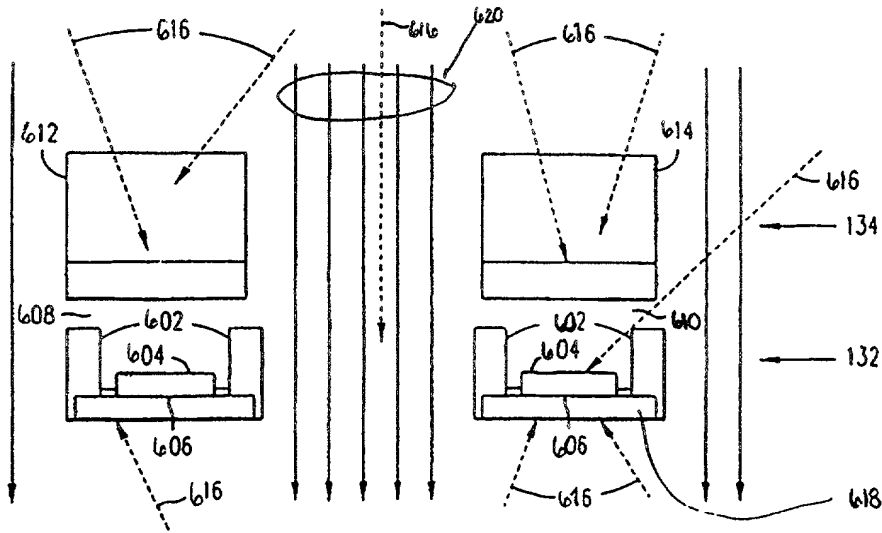


FIG. 6

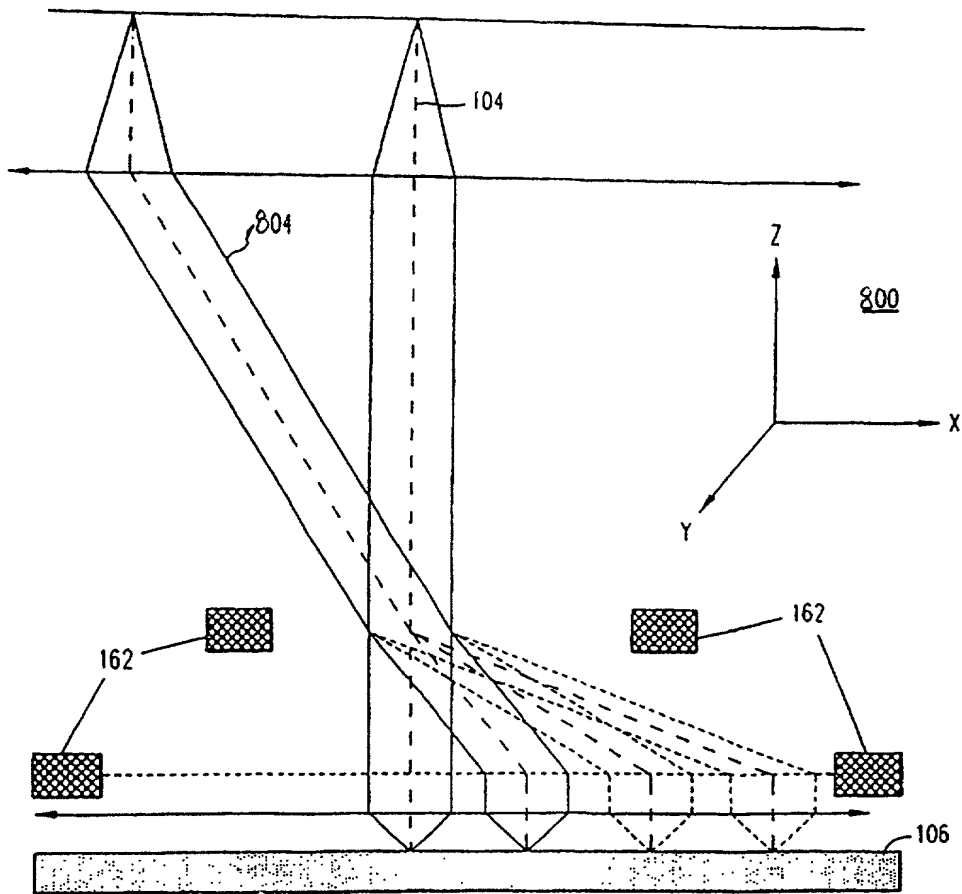
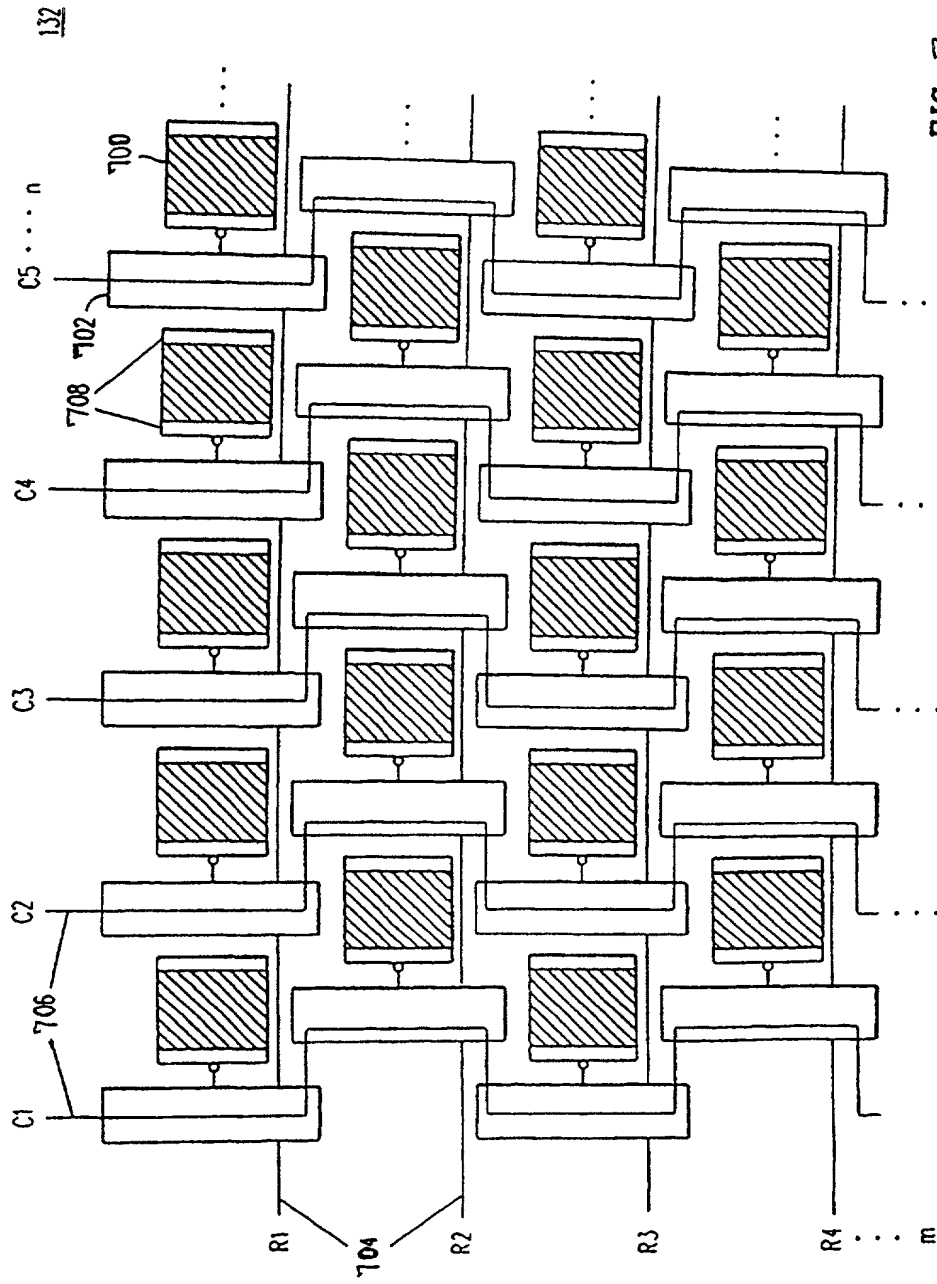


FIG. 8



904

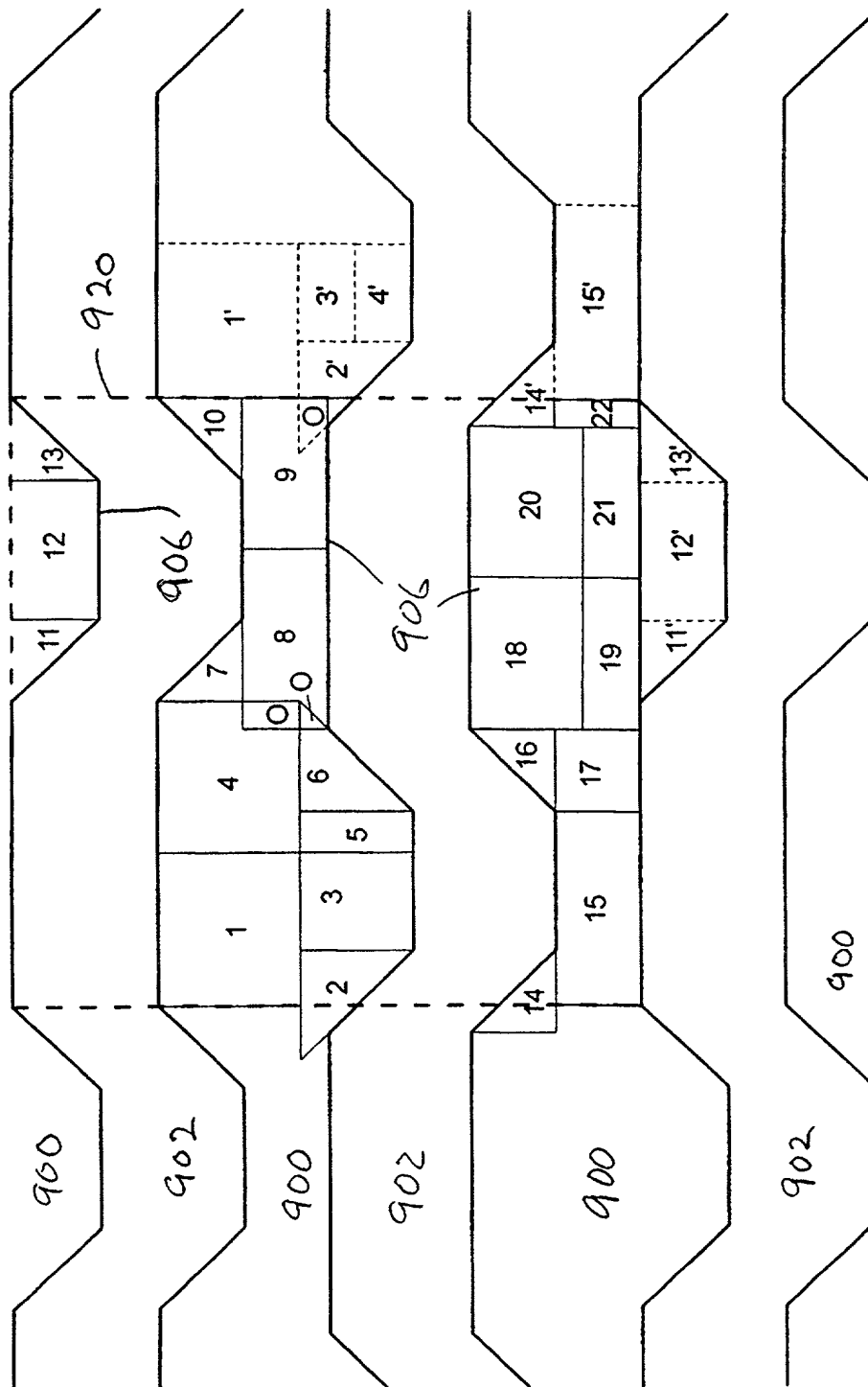


Figure 9A

904

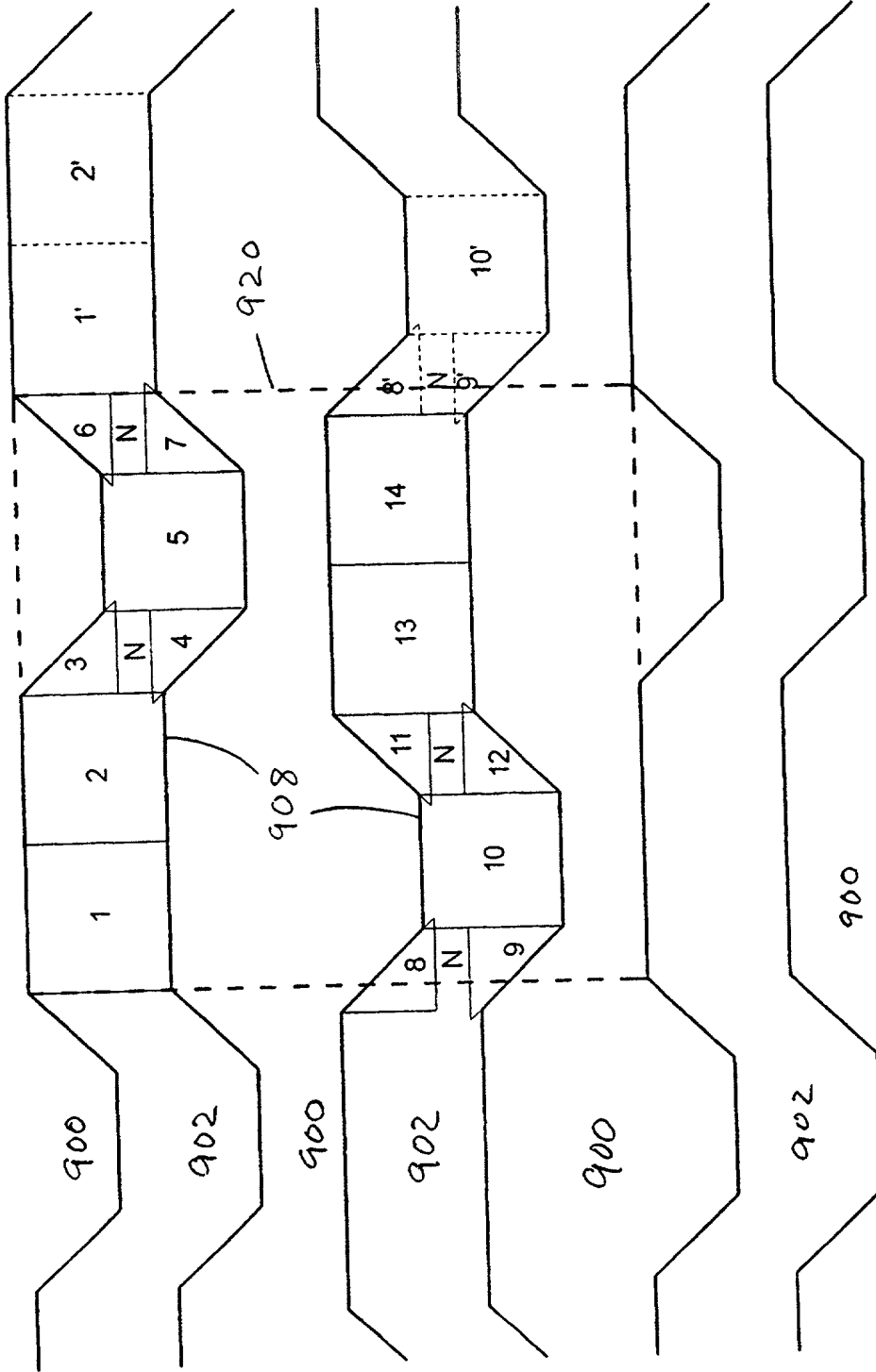


Figure 9B

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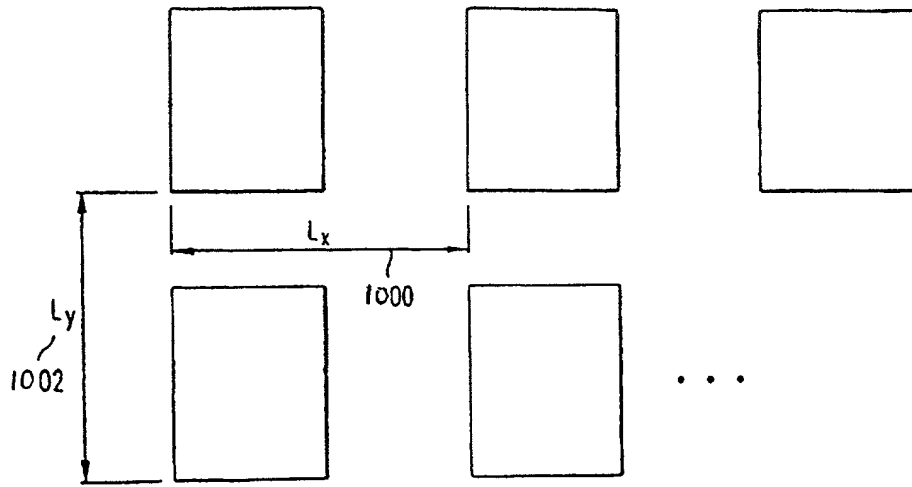


FIG. 10A

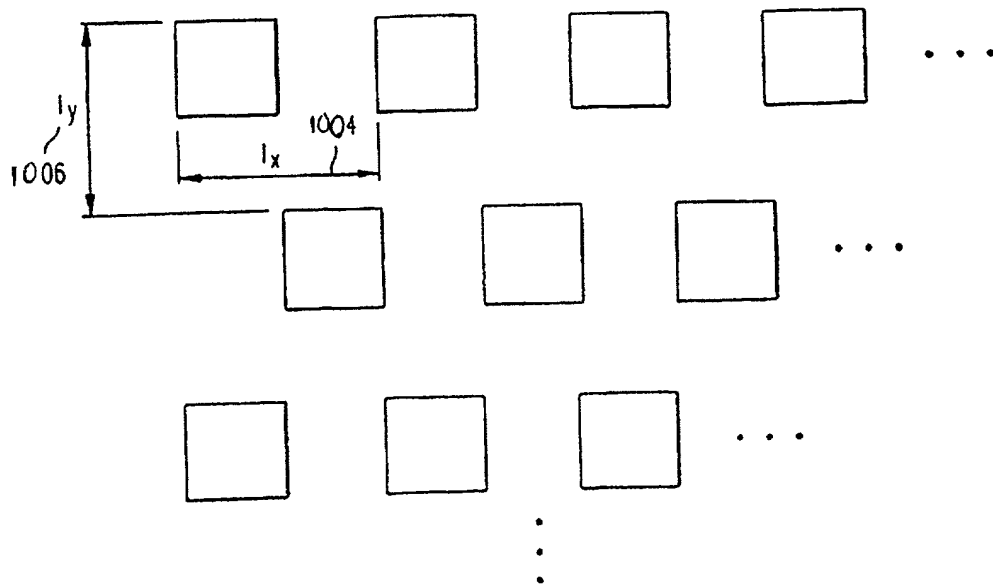


FIG. 10B

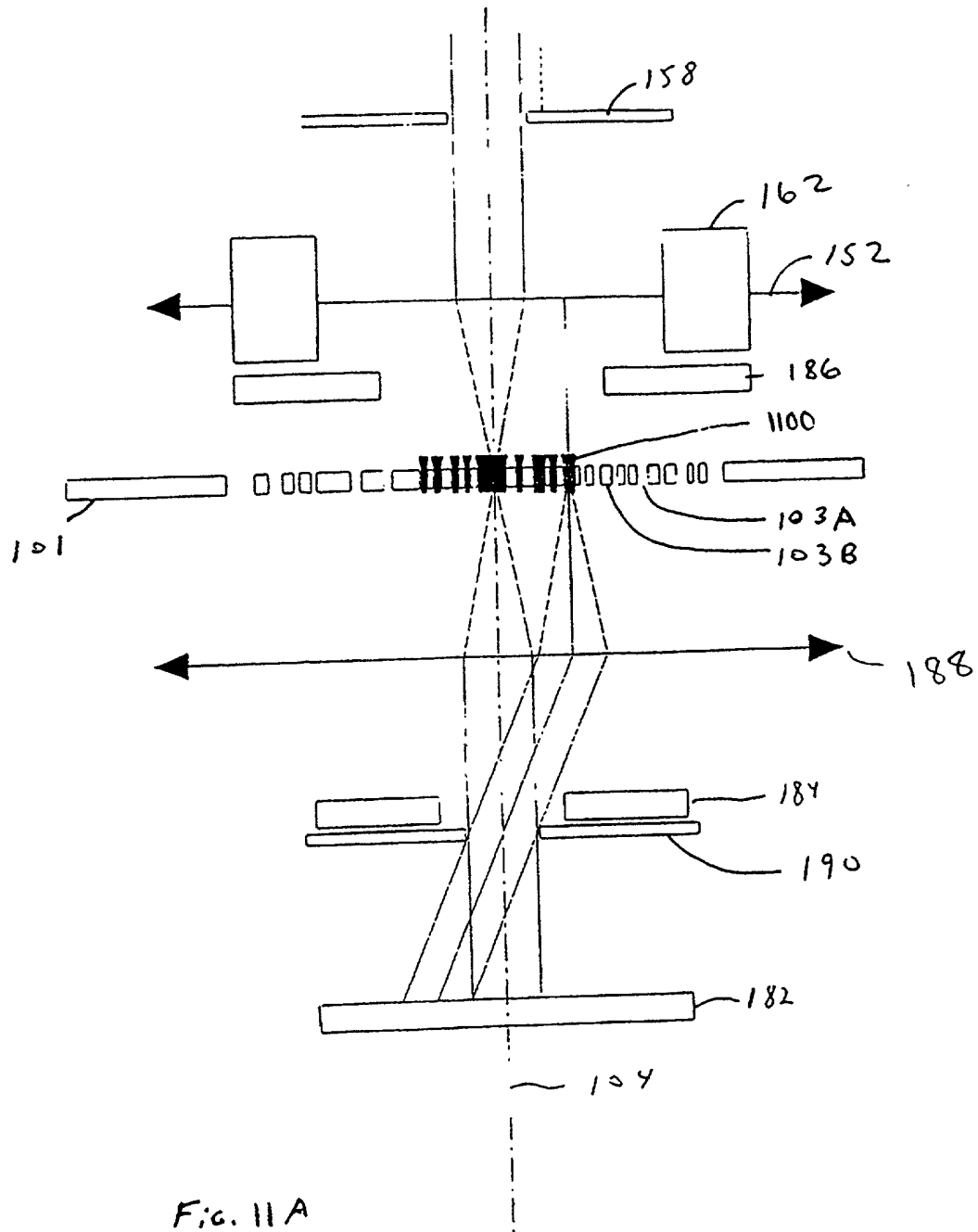


Fig. 11A

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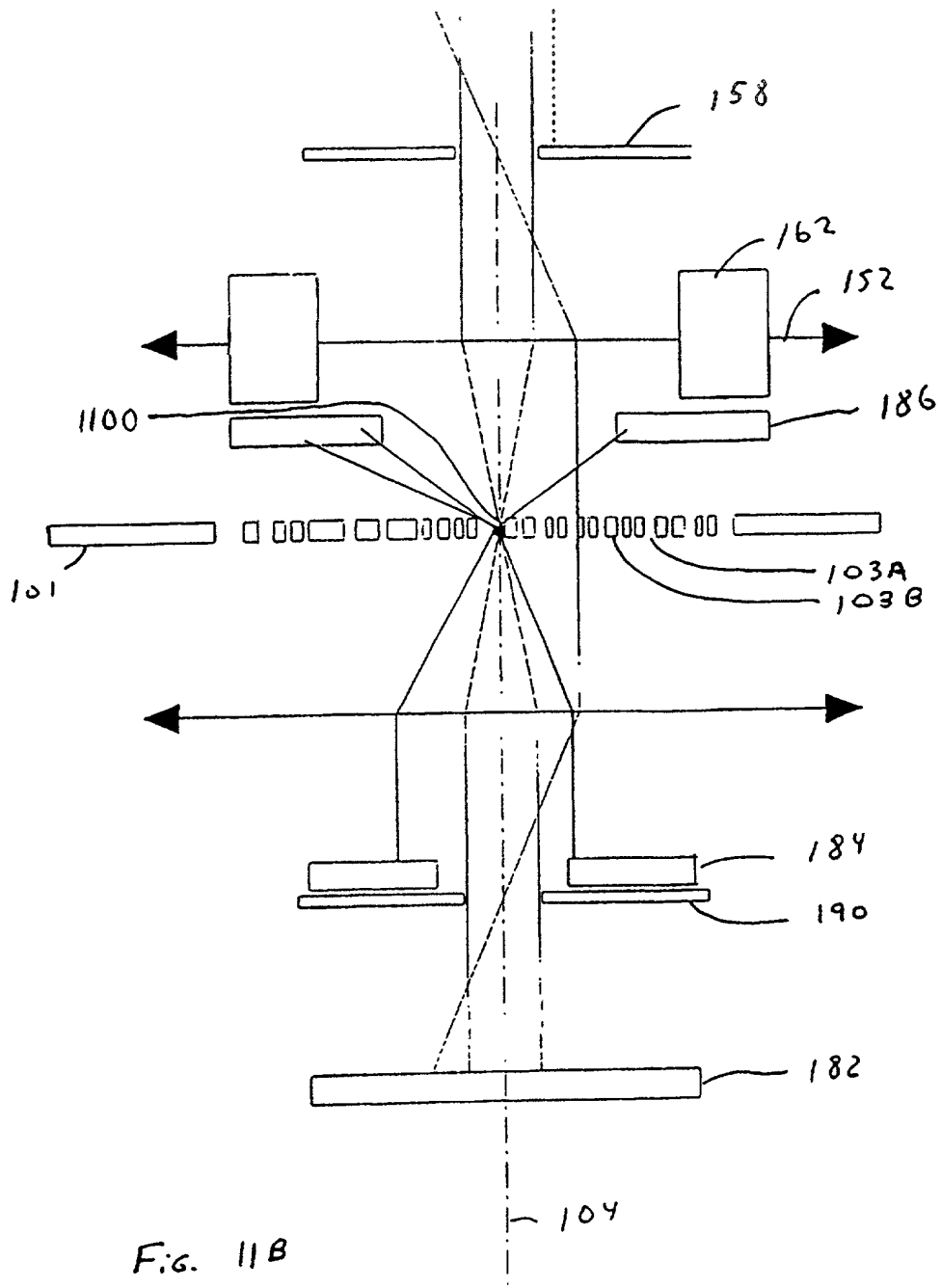
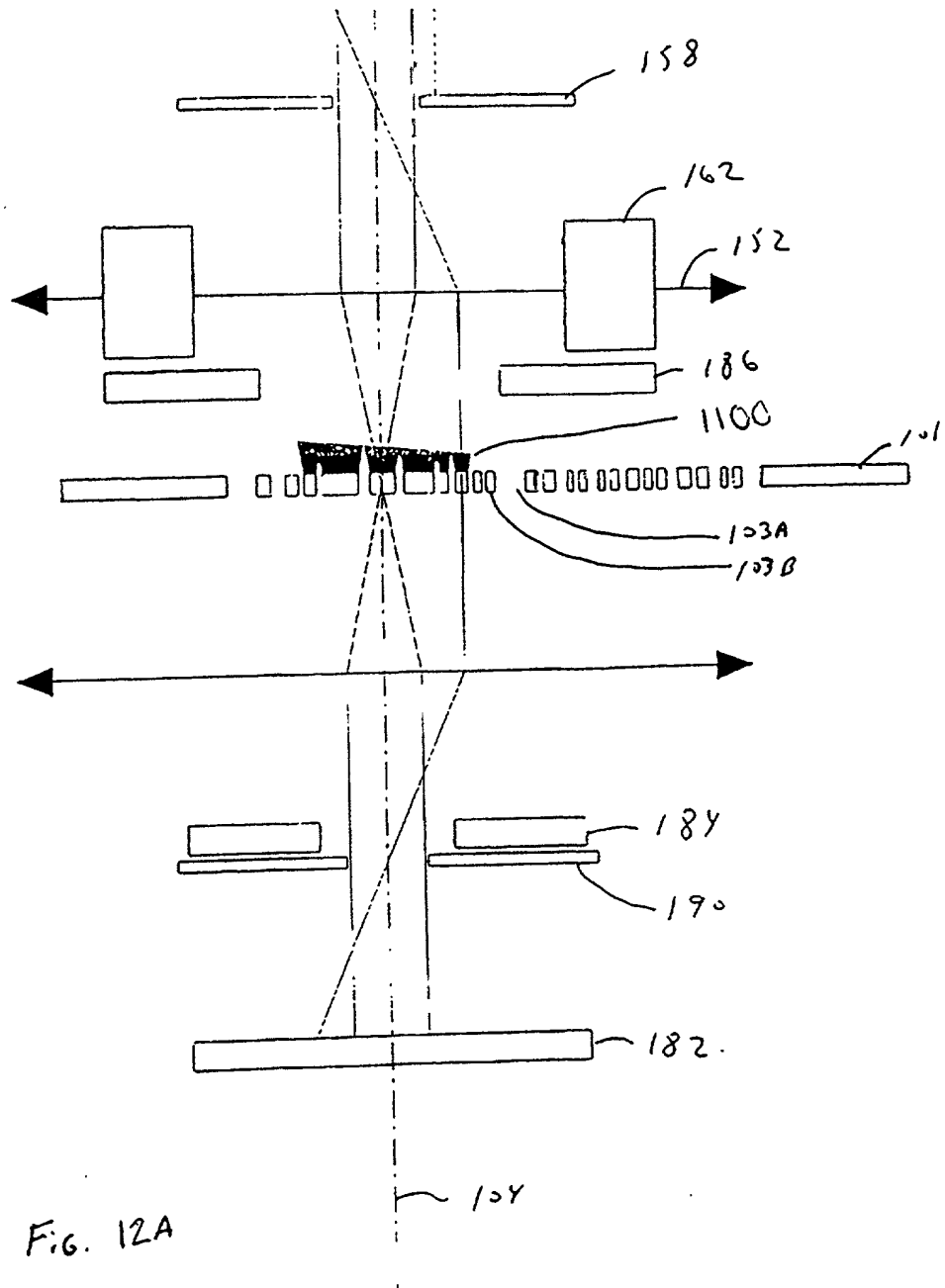


Fig. 11B

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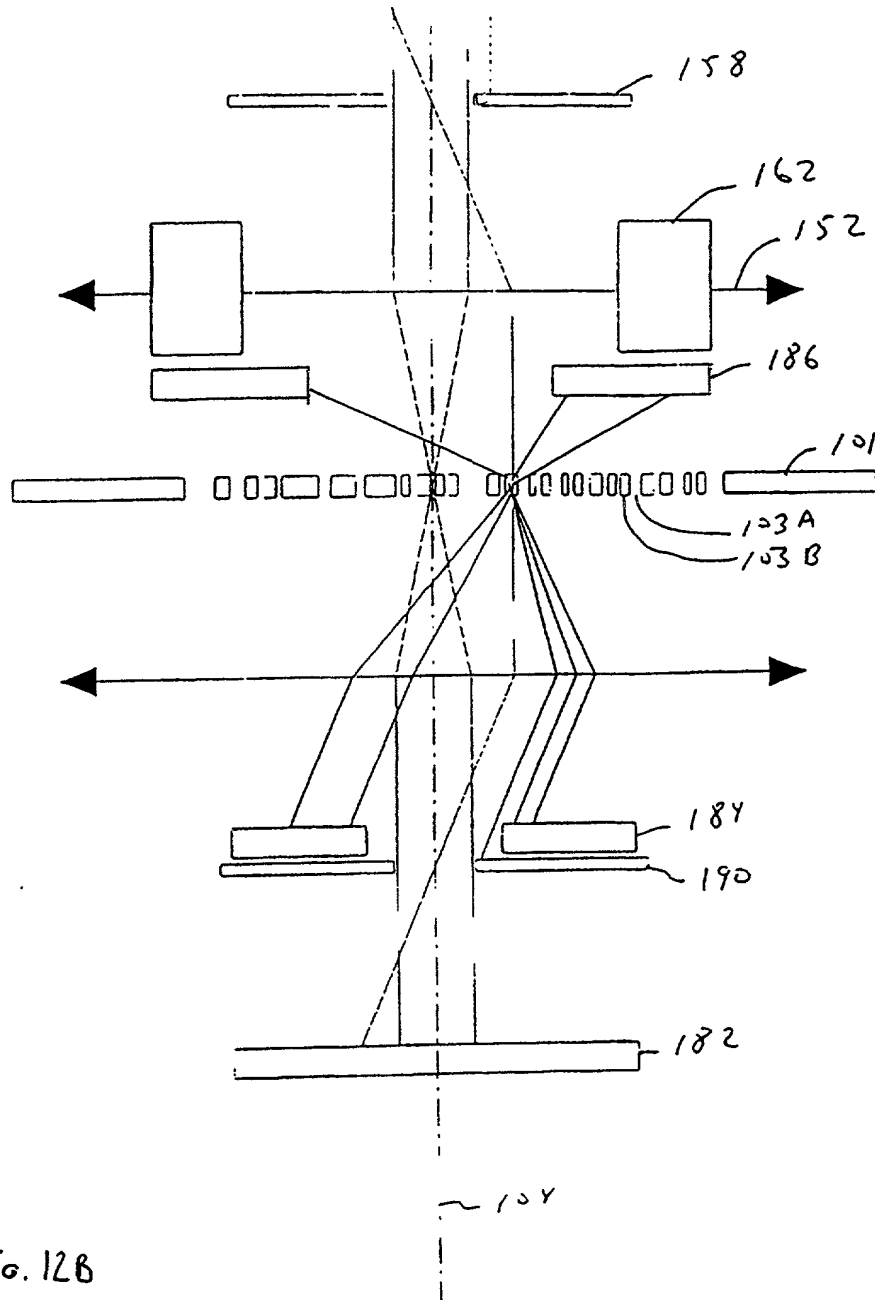


Fig. 12B

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Stencil Mask Defect Detection

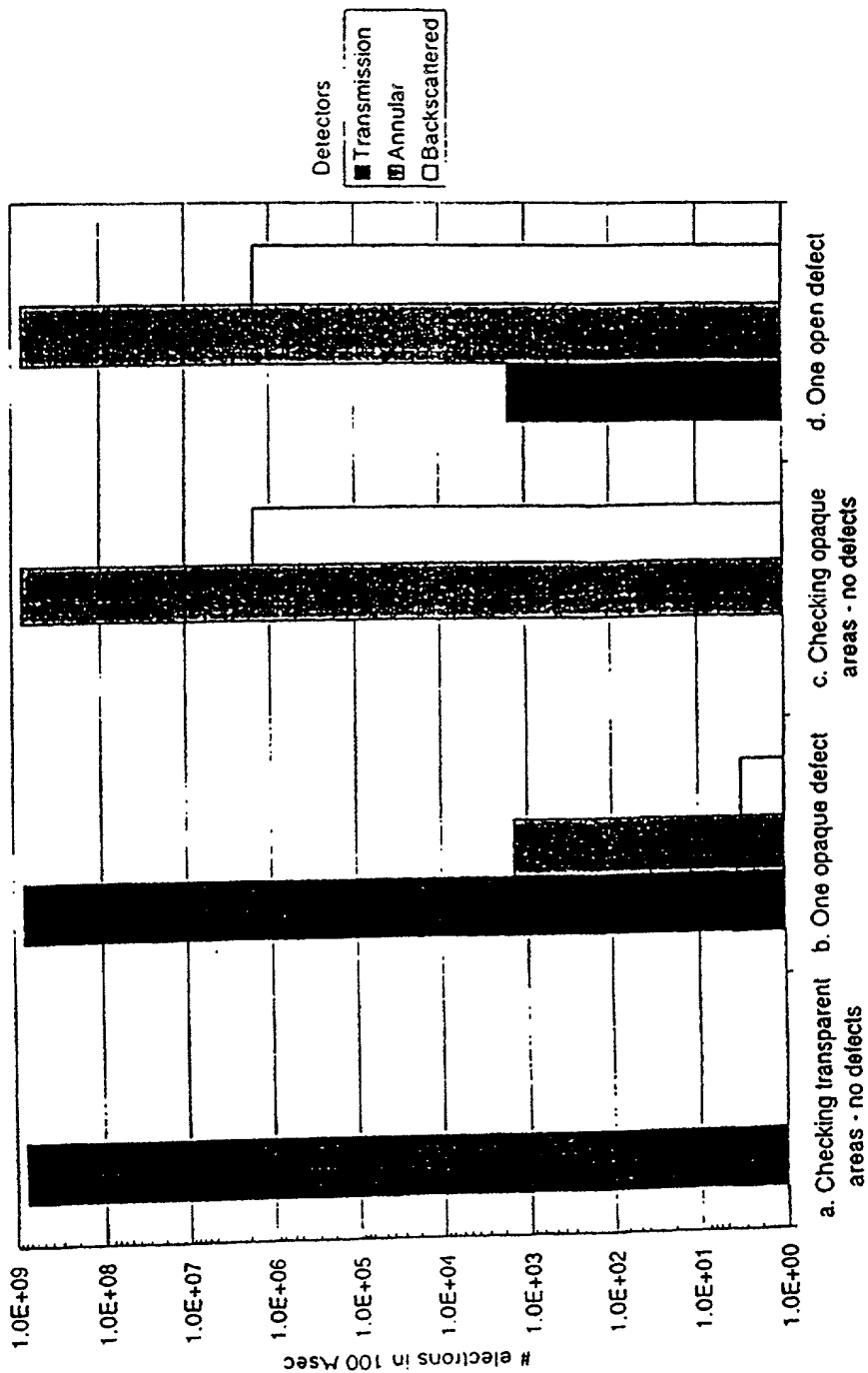
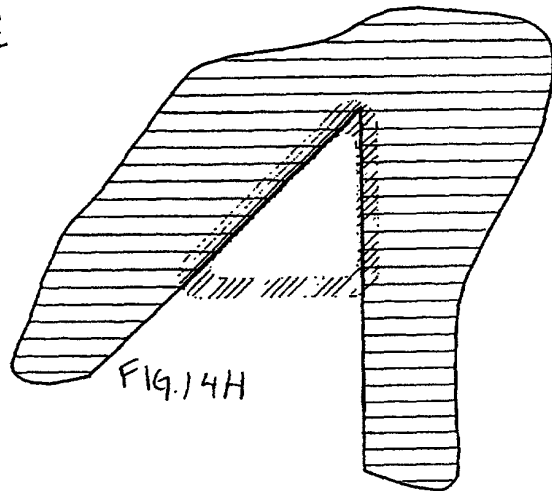
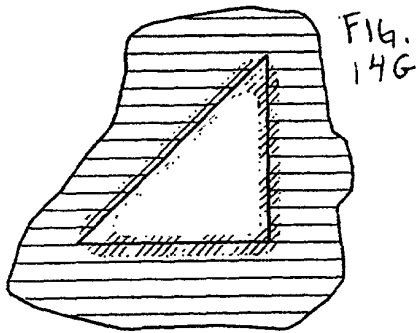
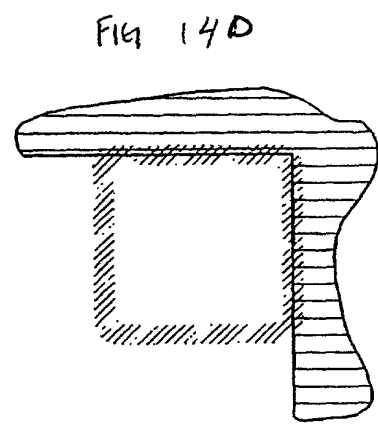
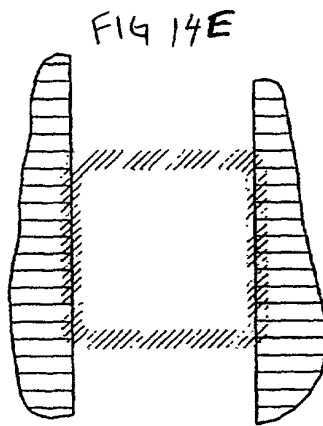
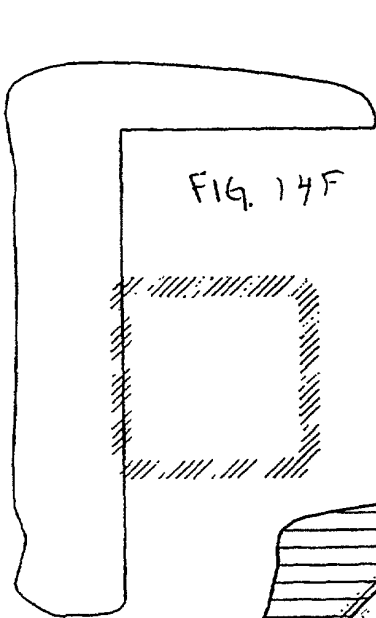
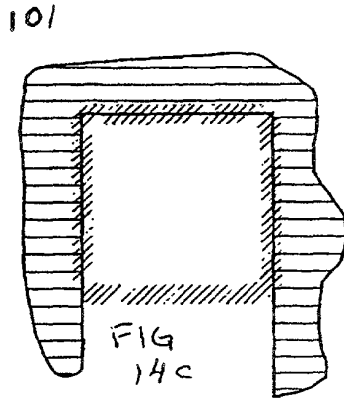
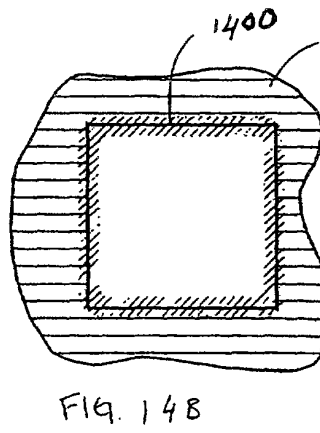
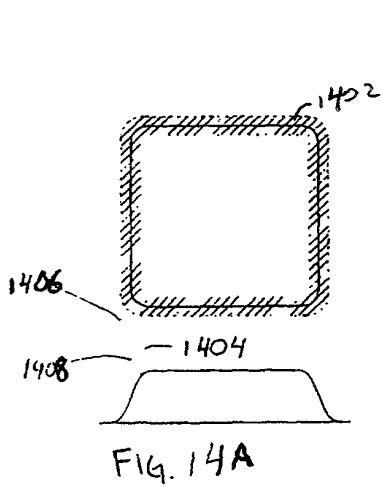


Fig. 13

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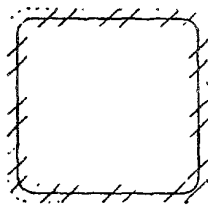
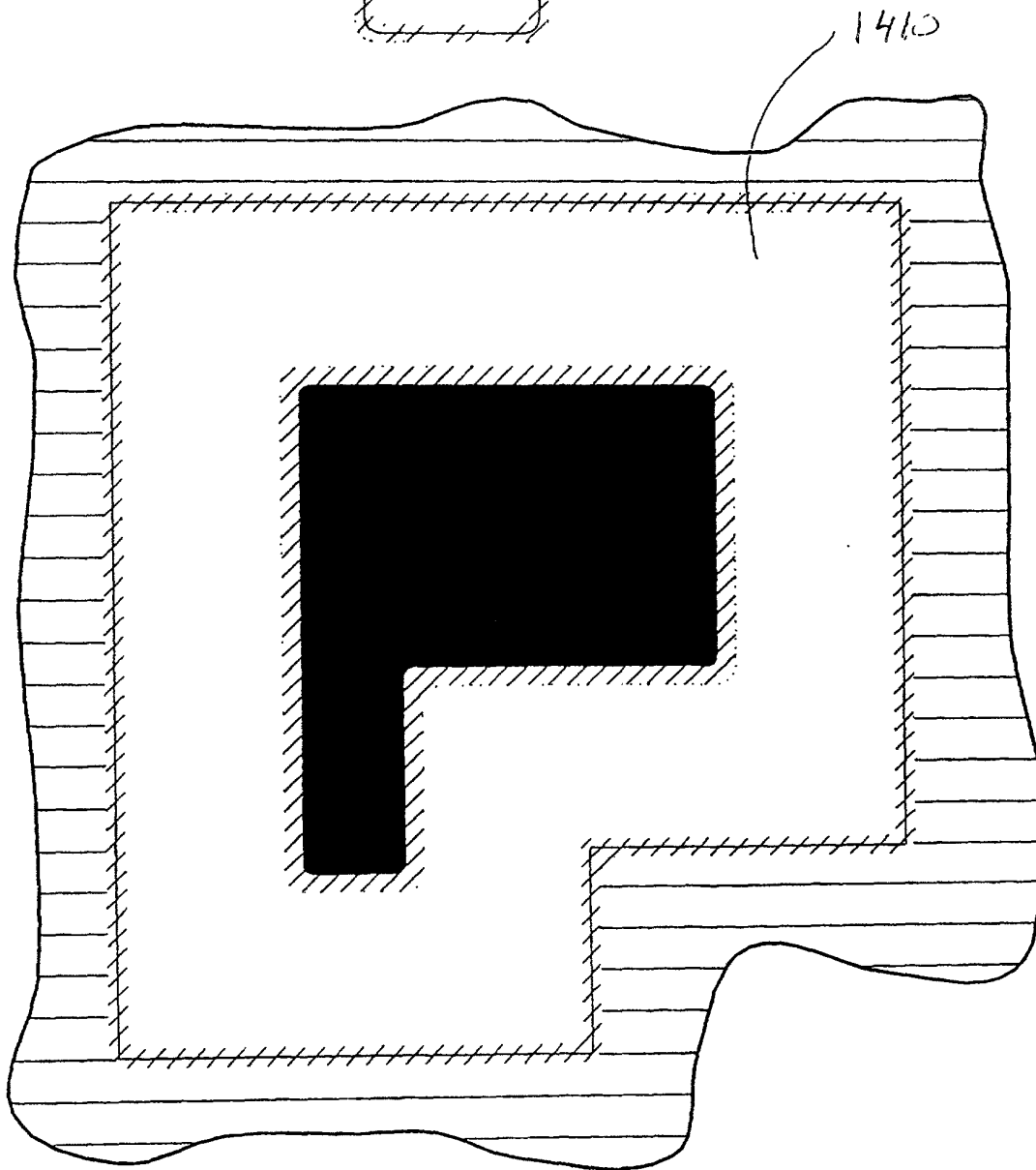


FIG.
14 I

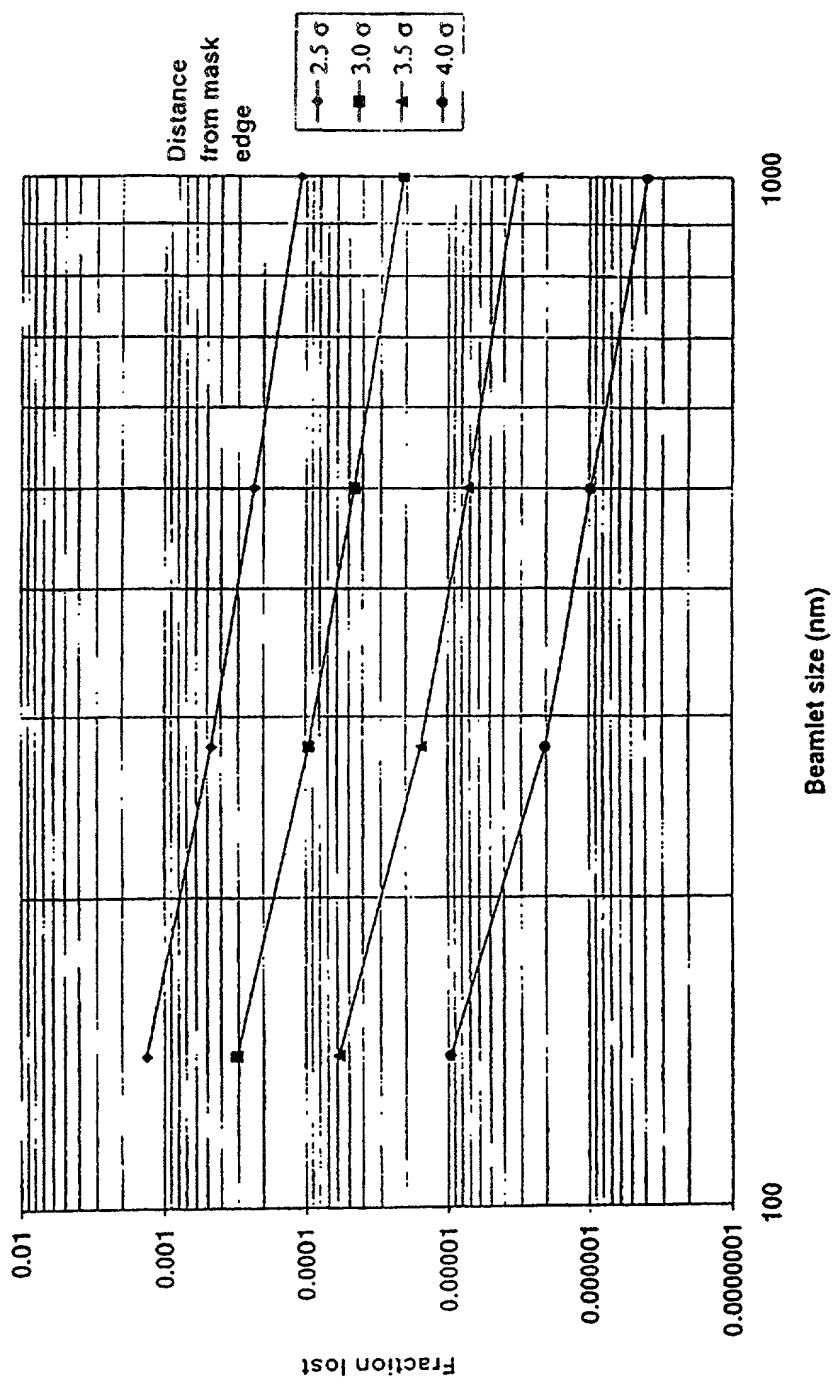


1410

FIG. 14 J

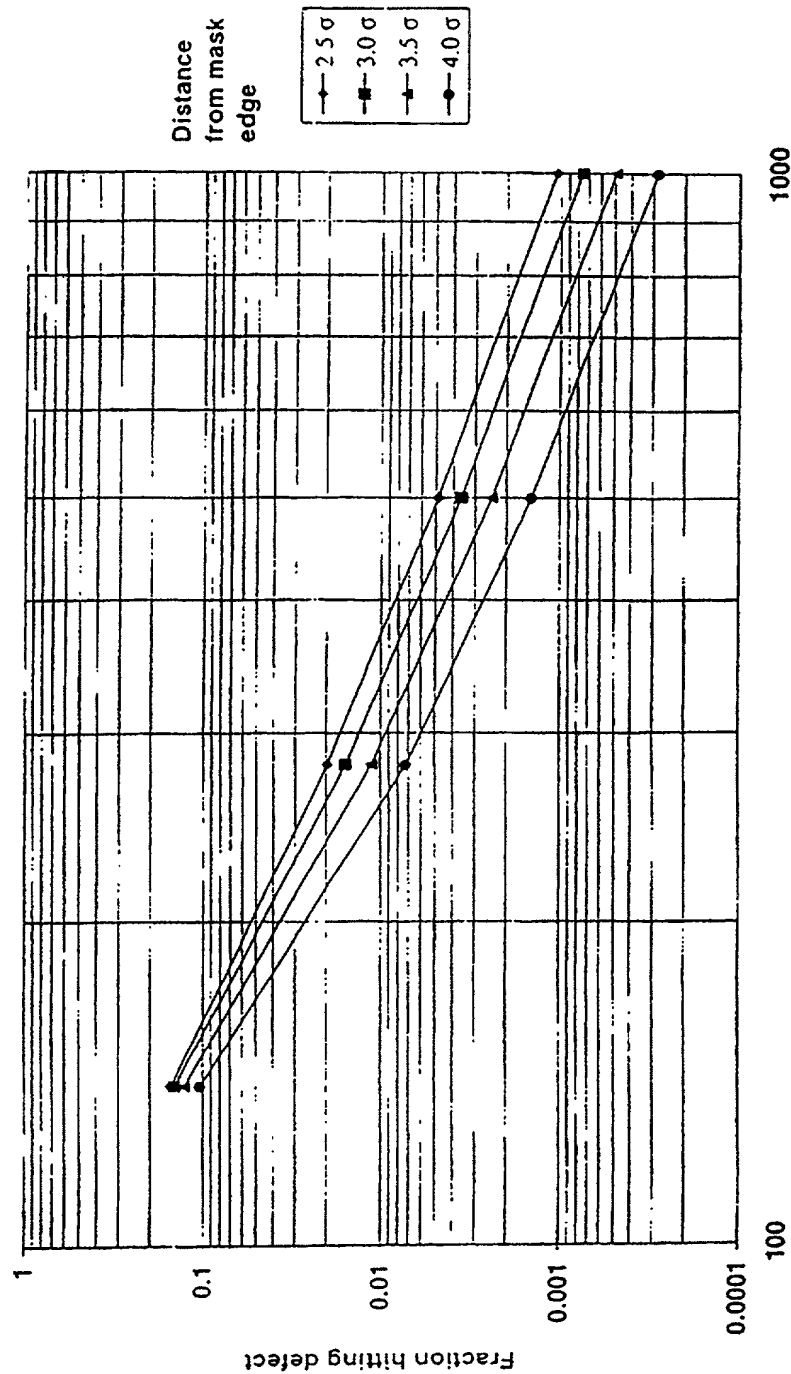
10026379.1 31801

Fraction of beamlet lost on mask (on all four sides)
edgewidth (12/88) = 30 nm; $1 \sigma = 12.77 \text{ nm}$



F.C. 15A

Fraction of beamlet hitting 50 nm defect
edgewidth (12/88) = 30 nm; 1 s = 12.77 nm



Beamlet size (nm)

FIG. 158

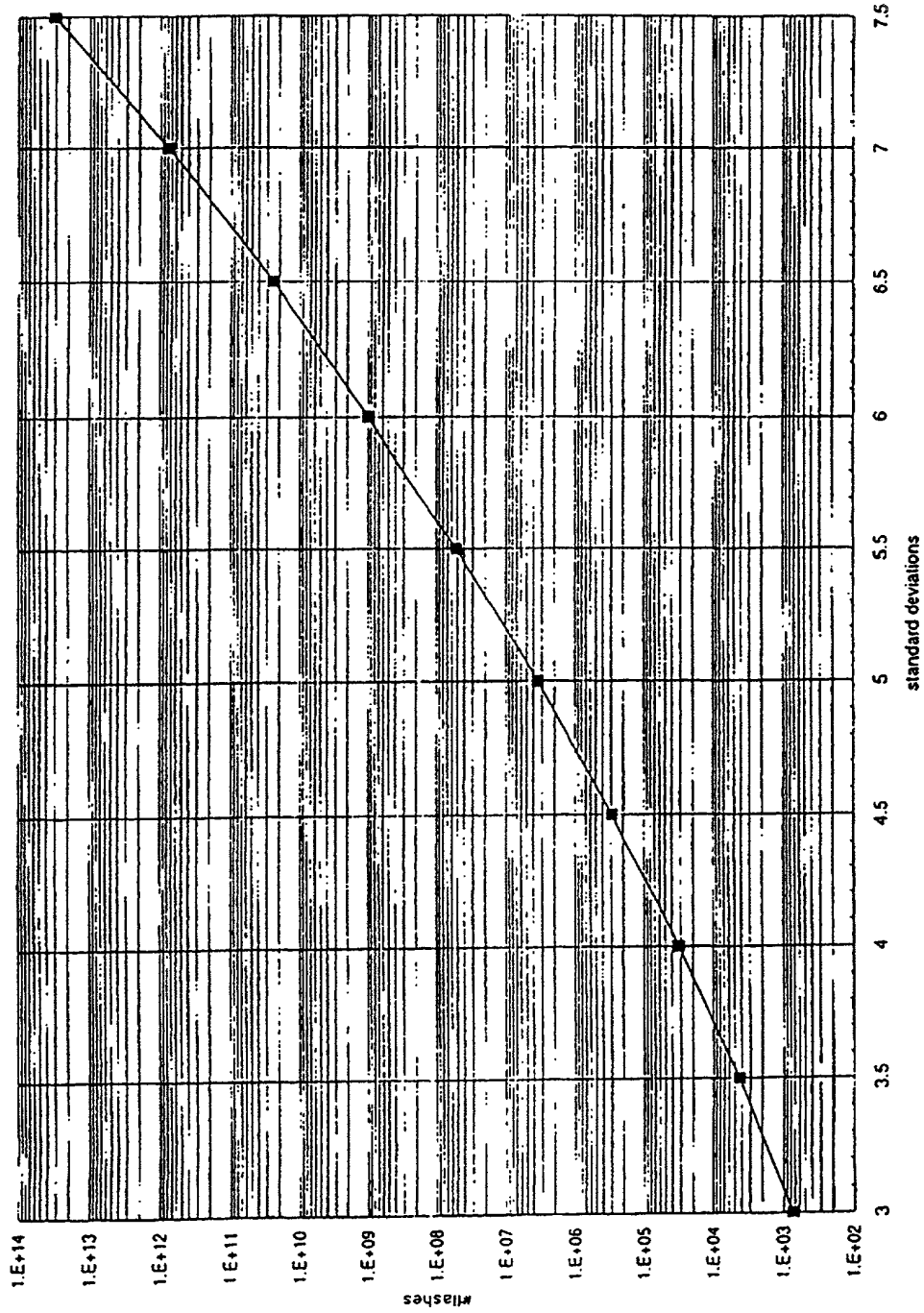


Fig. 15C

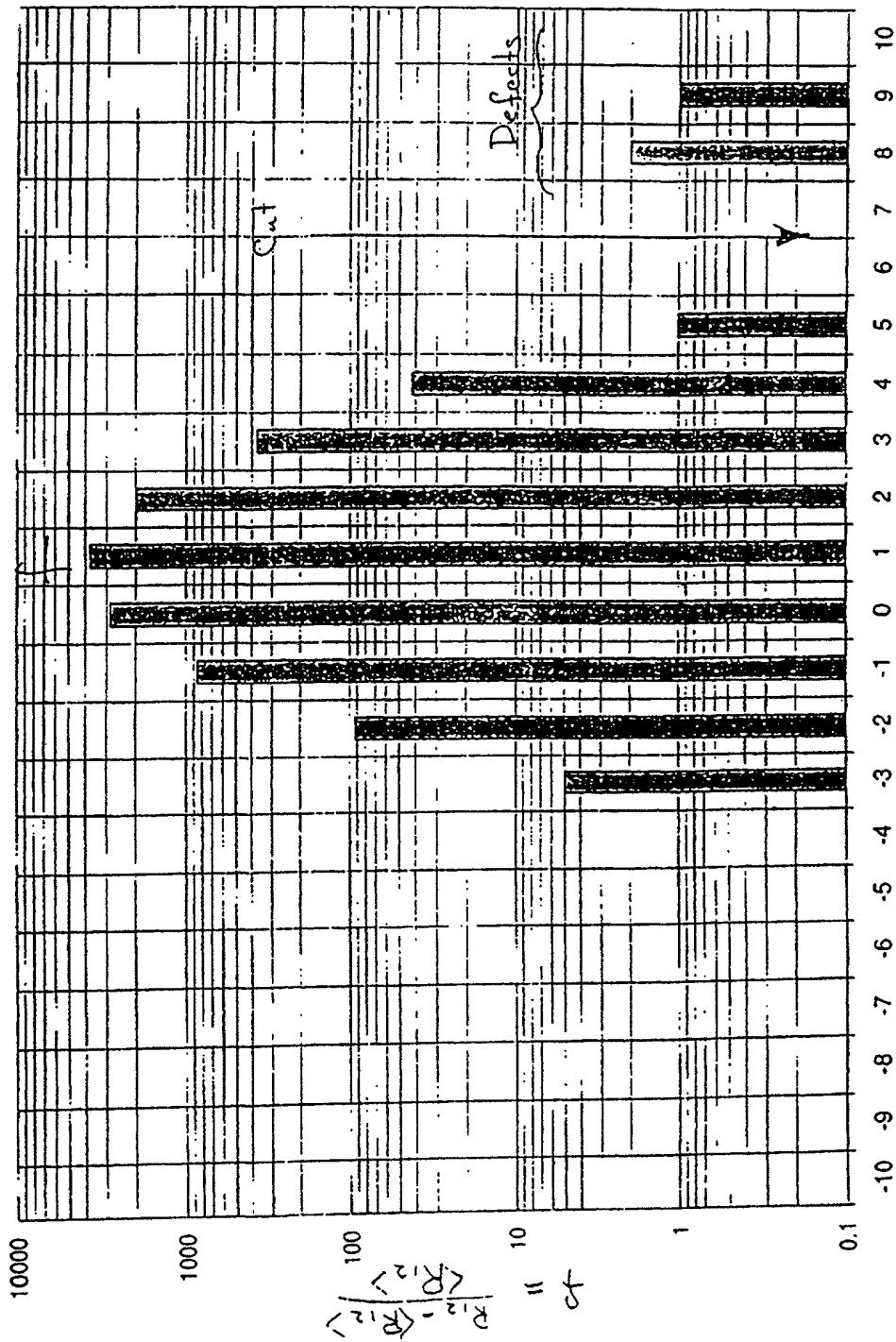


Fig 150

f/df for clear and opaque defects

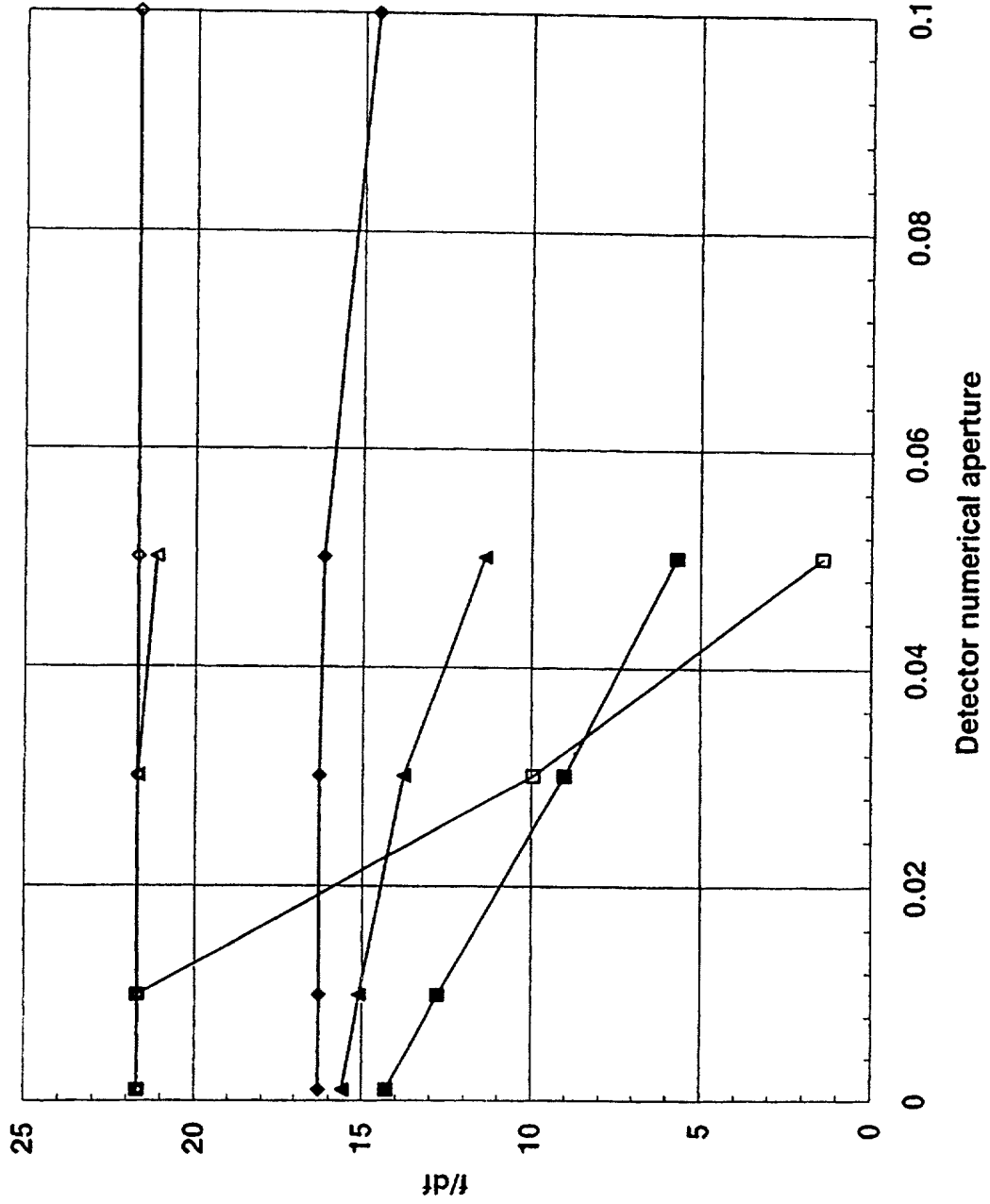


FIG 15E

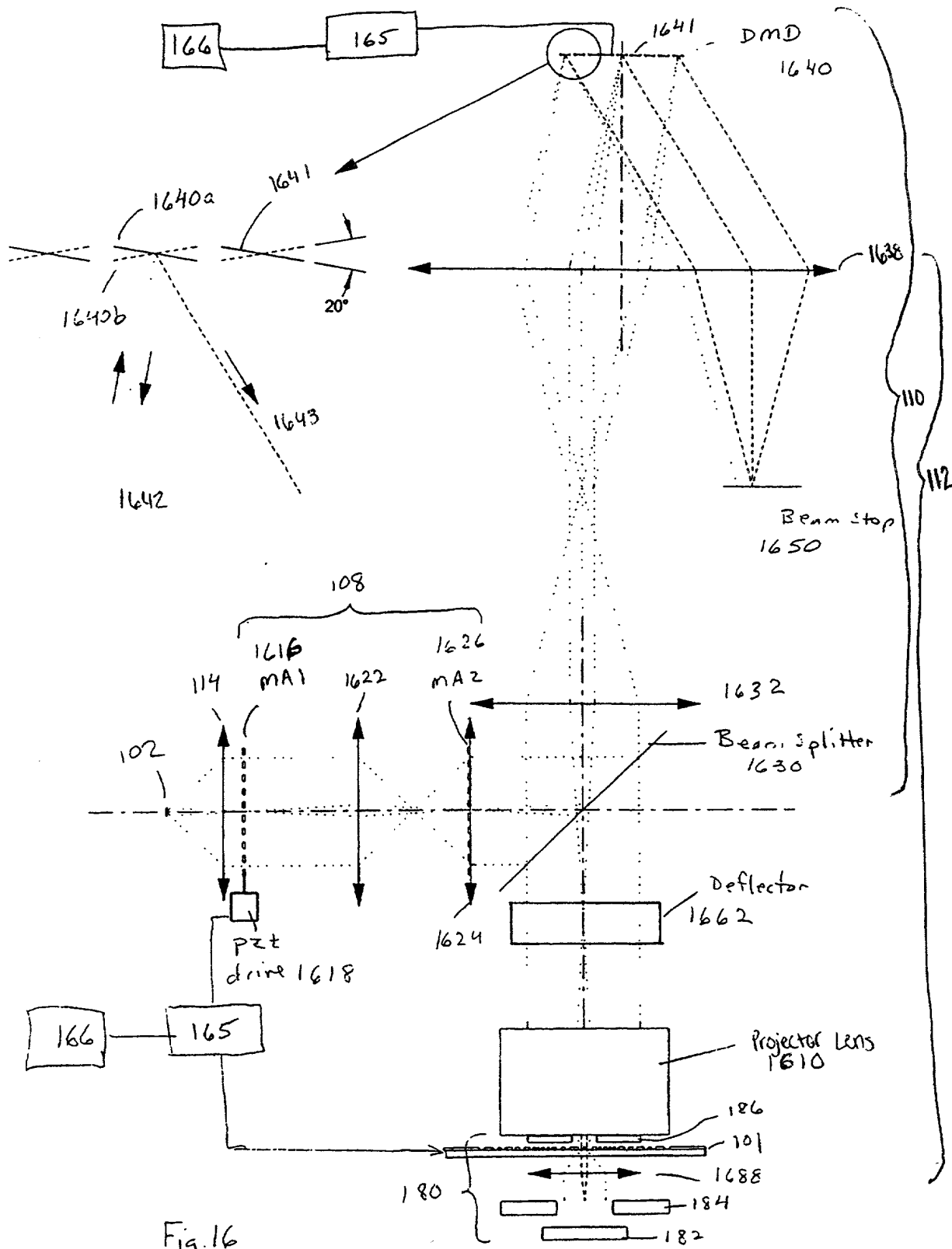


Fig. 16

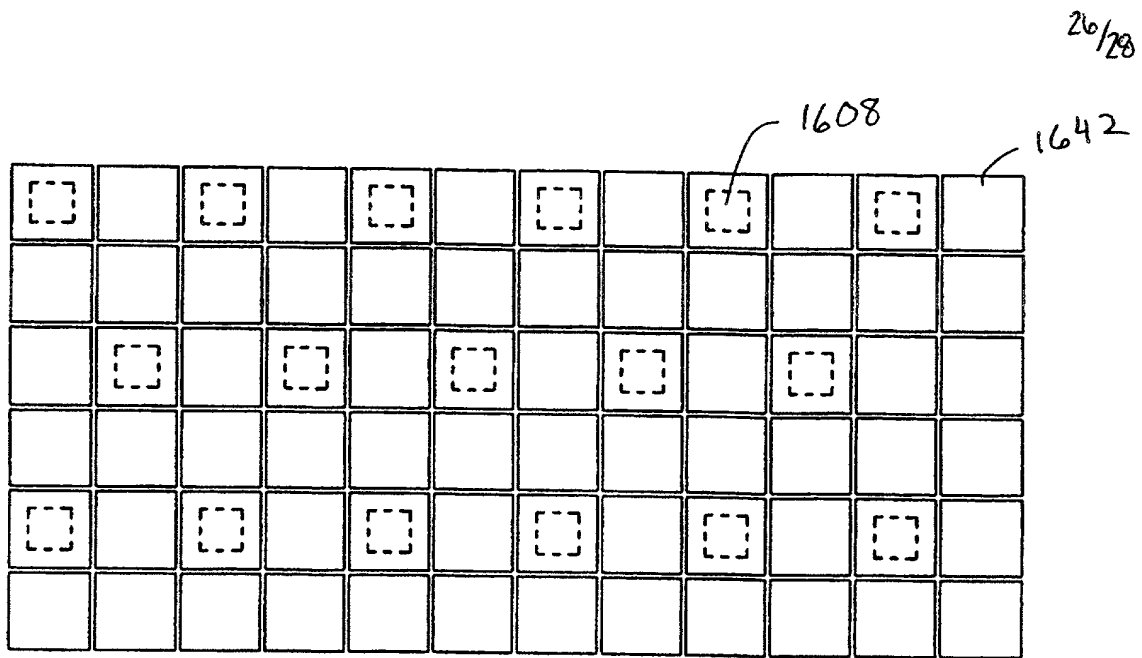


Fig. 17a

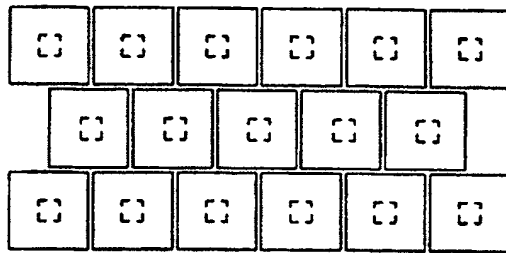


Fig. 17b

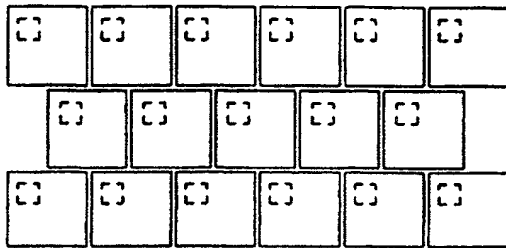


Fig. 17c

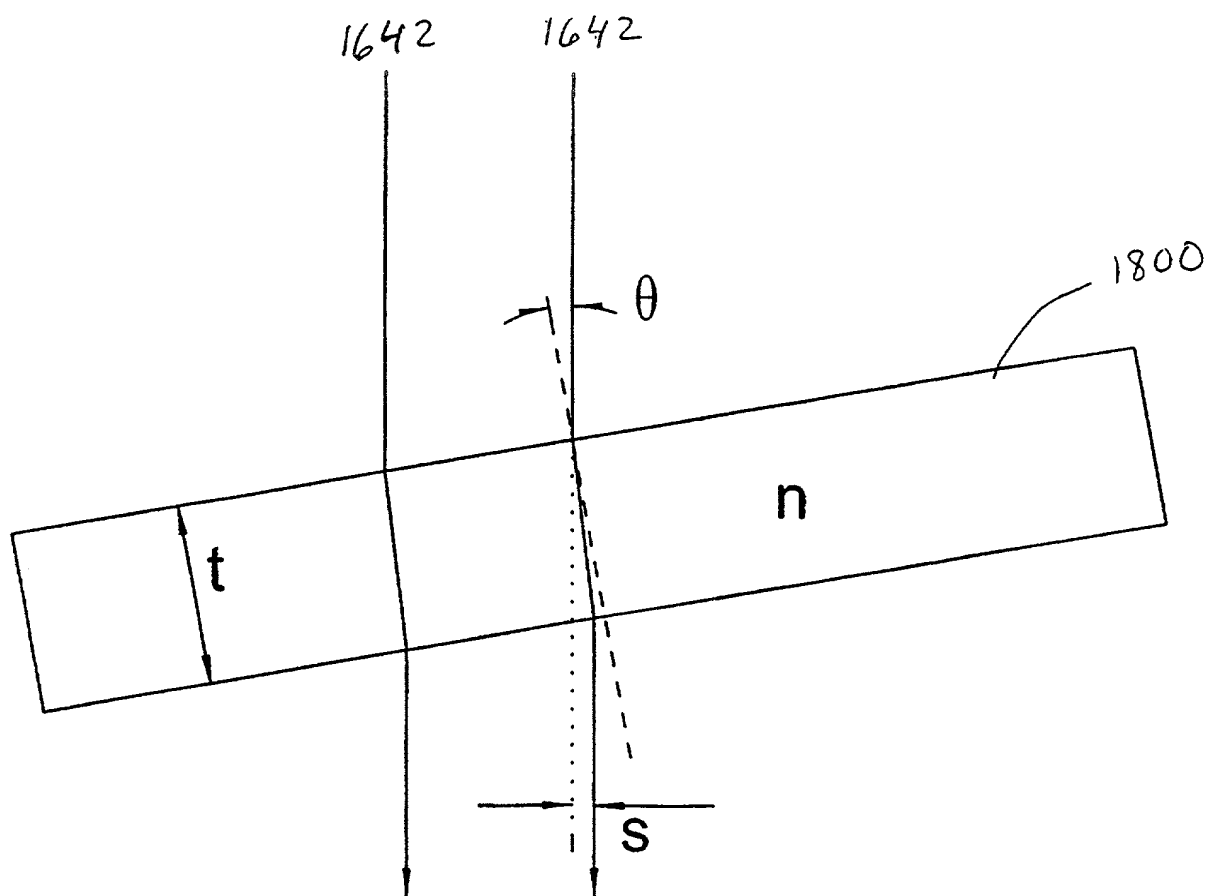


Fig 18

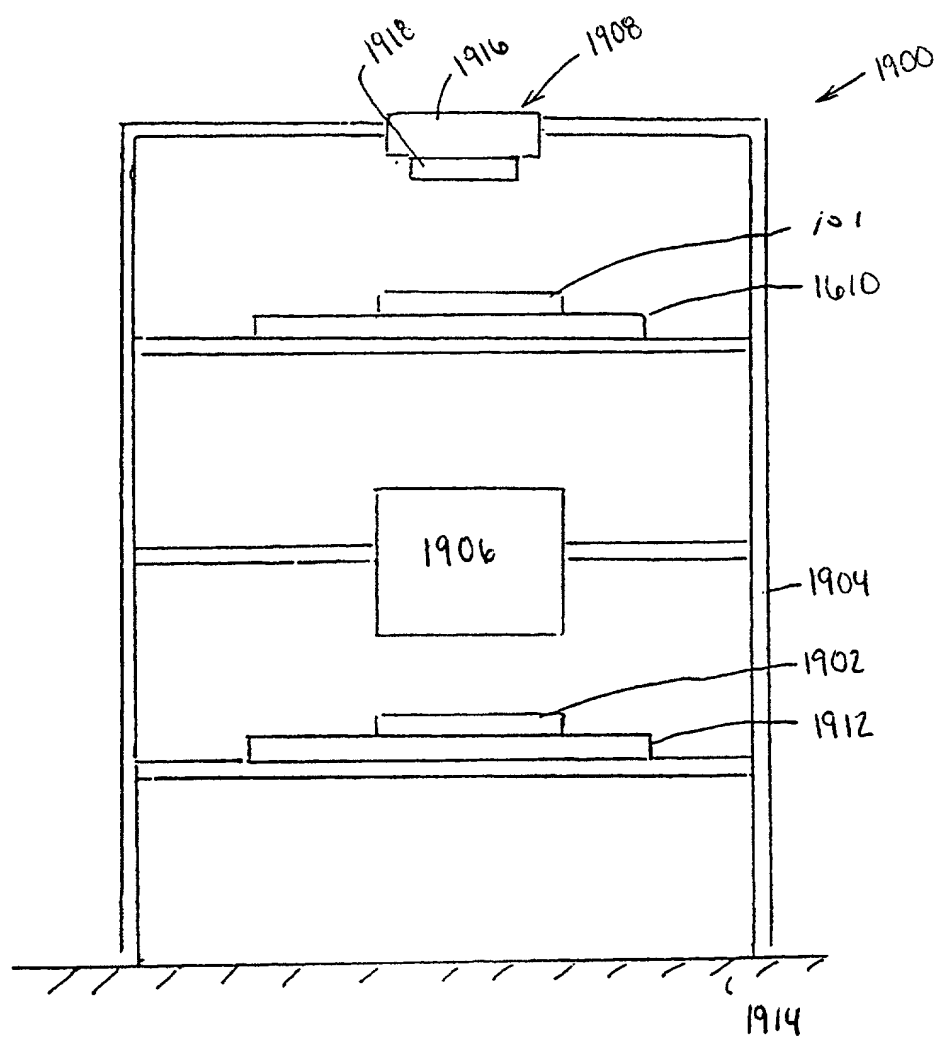


Fig 19